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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ATTY.'S DOCKET: BANIN=3A

In re Application of:)	Confirmation No.: 5414
)	
Uri BANIN et al)	
)	ATTN: PCT
I.A. Filing Date: 07/08/2004)	
371(c) Date:)	
)	October 13, 2006
U.S. Appln. No.: 10/564,036)	
)	
For: NANOPARTICLES FUNCTIONALIZED)	
PROBES AND METHODS...)	

COMMUNICATION RE: IDS

Customer Service Window, Mail Stop Amendment
Honorable Commissioner for Patents
U.S. Patent and Trademark Office
Randolph Building
401 Dulany Street
Alexandria, Virginia 22314

Sir:


On August 4, 2006, applicants filed Missing Parts together with a Preliminary Amendment and an Information Disclosure Statement (IDS). The IDS was five (5) pages in length, including three (3) pages of forms SB/08A/B.

A review of the IDS papers has revealed that the third page of the SB/08A/B did not identify the present application, although it is believed that all the pages were stapled together and that all copies listed, including citations AP through AS on that third page, were filed.

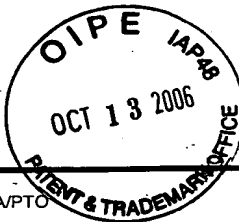
To complete the record (in the event that the third page of the form SB/08A/B were to be separated and lost), filed herewith is a duplicate third page in which the present application is fully identified at the top thereof.

Respectfully submitted,

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BN/SB/08A/B

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet 3 of 3

Complete if Known

Application Number	10/564,036
Filing Date	July 8, 2004
First Named Inventor	Uri BANIN et al
Group Art Unit	
Examiner Name	
Attorney Docket Number	BANIN=3A

NON PATENT LITERATURE DOCUMENTS / OTHER INFORMATION

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
	AP	ANDERSON, M. "Locally enhanced Raman spectroscopy with an atomic force microscope"; Applied Physics Letters, Vol. 76, Number 21, pp.3130-3132, May 22, 2000	
	AQ	VICKERY, S.A. et al. "Combining AFM and FRET for high resolution fluorescence microscopy"; Journal of Microscopy, Vol. 202, pp.408-412, May 2001	
	AR	OKAMOTO, T. et al. "Near-Field scanning Optical Microscope Using a Gold Particle"; J. Appl. Phys. Vol.36, XP-000732147, pp.L166-L169, 1997	
	AS	WESSEL, J. "Surface-enhanced optical microscopy"; J. Opt. Soc. AM. B/Vol. 2, No. 9, XP-002300715, September 1985	

Examiner
SignatureDate
Considered

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.